

## Introduction

This document explains how to use the Microchip Metrology library, and it is considered as a complement of the PIC32CXMTx Metrology Reference Guide (*DS50003461*). It describes the calibration procedure as well as other complex features of the library, such as the waveform capture.

For additional information, refer to the full description of the registers of the "PIC32CXMTx Metrology Reference Guide (*DS50003461*)".

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## 1. Configuration

### 1.1. Current Conversion Factor

#### 1.1.1. Current Transformer (CT)

$$K_{Ix} = \frac{K_{coil}}{G_{PGA} \times R_{LOAD}}$$

Where:

$K_{coil}$  is the CT transformer ratio

$G_{PGA}$  is the ADC current channel gain

$R_{LOAD}$  is the total burden resistance

**Example:**

If  $K_{coil} = 1000$ ,  $G_{PGA} = 1$  and  $R_{LOAD} = 3.24$  ohm, then the result is:

$$K_{Ix} = 1000 / (1 * 3.24) = 308.642$$

The metrology firmware uses uQ22.10 to represent both integer and fractional numbers; therefore, the value to set is:

$$K_{Ix} = \text{ROUND}(308.642 * 2^{10}) = 0x0004D291$$

#### 1.1.2. Resistive Shunt

$$K_{Ix} = \frac{1}{G_{PGA} \times R_{shunt}}$$

**Example:**

If  $R_{shunt} = 100$  uOhm = 0.0001 ohm and  $G_{PGA} = 8$ , then the result is:

$$K_{Ix} = 1 / (8 * 0.0001) = 1250$$

The metrology firmware uses uQ22.10 to represent both integer and fractional numbers; therefore, the value to set is:

$$K_{Ix} = \text{ROUND}(1250 * 2^{10}) = 0x00138800$$

#### 1.1.3. Rogowski Coil

$$K_{Ix} = \frac{K_{Rogowski} (60Hz)}{G_{PGA}}$$

Where:

60 Hz is the Rogowski coil scale factor at 60 Hz and it represents the coil sensitivity, measured in millivolts per ampere (mV/A) at 60 Hz.

**Note:** The scale factor  $K_{Rogowski}$  is defined at the reference frequency  $f_r = 60$  Hz because the Digital Integrator (DI) filter was designed for unity gain at 60 Hz. If it is desired to use  $K_{Rogowski}$  defined at another frequency, the gain of the DI filter must be accounted for in the computation as follows:

$$K_{Ix} = \frac{K_{Rogowski} (f)}{G_{PGA} \times K_{di}(f)}$$

Where:

$$K_{di(f)} = 60 \text{ Hz/f}$$

For example, a Rogowski coil is used with an output of 500 uV/A at 60 Hz (or 416.6 uV/A at 50 Hz) and a  $G_{PGA} = 4$ , then,

$$K_{Rogowski}(60 \text{ Hz}) = 1000000 / 500 = 2000$$

$$K_{Ix} = 2000 / 4 = 500$$

The metrology firmware uses uQ22.10 to represent both integer and fractional numbers; therefore, the value to set is:

$$K_{Ix} = \text{ROUND}(500 * 2^{10}) = 0x007D000$$

**Note:** The METER\_TYPE control register must be configured correctly: 0x00000CCC for CT, 0x00000DDD for SHUNT, and 0X00000EEE for Rogowski coil.

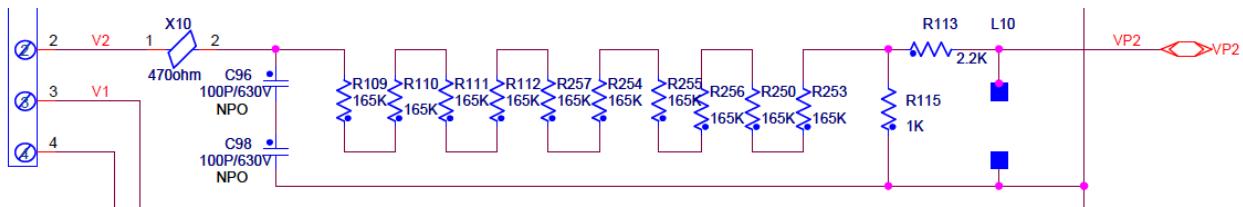
## 1.2. Voltage Conversion Factor

$K_{Vx}$  is the voltage divider ratio.

### Example:

Voltage sensor inputs circuit is illustrated in the figure below.

**Figure 1-1. Voltage Sensors Input Circuit**



$$K_{Vx} = \frac{R109 + R110 + R111 + R112 + R257 + R254 + R255 + R256 + R250 + R253 + R115}{R115} = 1651$$

The metrology firmware uses uQ22.10 to represent both integer and fractional numbers; therefore, it is recommended this to be set:

$$K_{Vx} = \text{ROUND}(1651 * 2^{10}) = 0x0019CC00$$

## 1.3. Sag, Swell, and Interrupt

The metrology firmware supports respective sag, swell, interrupt thresholds for all voltage channels x (where x = [A, B, C]):

$$\text{SAG_THRESHOLD\_Vx} = \left( \frac{V_{\text{SAG-RMS}}}{K_{Vx}} \right)^2 \times 2^{32}$$

$$\text{SWELL_THRESHOLD\_Vx} = \left( \frac{V_{\text{SWELL-RMS}}}{K_{Vx}} \right)^2 \times 2^{32}$$

$$\text{INTERRUPT_THRESHOLD\_Vx} = \left( \frac{V_{\text{INTERRUPT-RMS}}}{K_{Vx}} \right)^2 \times 2^{32}$$

There are respective flags SAG\_DET\_Vx, SWELL\_DET\_Vx, PH\_X\_ACTIVE to indicate the sag, swell, interrupt status for every voltage channels. The sag and swell flags are updated every half cycle and the interrupt flags are updated every full cycle.

#### Example:

If  $V_{SAG-RMS} = 220 * 0.8 = 176V$  and  $K_{Vx} = 1651$ , then the result is:

$$SAG\_THRESHOLD\_Vx = ((220 * 0.8 / 1651)^2) * 2^{32} = 0x02E8C044$$

If  $V_{SWELL-RMS} = 220 * 1.2 = 264V$  and  $K_{Vx} = 1651$ , then the result is:

$$SWELL\_THRESHOLD\_Vx = ((220 * 1.2 / 1651)^2) * 2^{32} = 0x068BB09A$$

If  $V_{INTERRUPT-RMS} = 220 * 0.5 = 110V$  and  $K_{Vx} = 1651$ , then the result is:

$$INTERRUPT\_THRESHOLD\_Vx = ((220 * 0.5 / 1651)^2) * 2^{32} = 0x0122EB1B$$

## 1.4. Pulse Test Constant

The metrology library version v03.04.00 introduces significant updates to the configuration of pulse test constants. Previously, four registers were used to set pulse test constants:

- P\_K\_t: Active energy pulse generator constant
- Q\_K\_t: Reactive energy pulse generator constant
- I\_K\_t: Current energy pulse generator constant
- S\_K\_t: Apparent energy pulse generator constant

In version v03.04.00, these registers have been replaced with the following:

- PULSE0\_K\_t: Pulse test constant for PULSE 0
- PULSE1\_K\_t: Pulse test constant for PULSE 1
- PULSE2\_K\_t: Pulse test constant for PULSE 2

The units for PULSE0\_K\_t, PULSE1\_K\_t, and PULSE2\_K\_t are determined by the energy type configuration of the corresponding pulse, which is set through the PULSE0\_CTRL, PULSE1\_CTRL, and PULSE2\_CTRL control registers:

- [Wh/pulse] for active energy
- [VARh/pulse] for reactive energy
- [VAh/pulse] for apparent energy
- [Amp<sup>2</sup>-h/pulse] for current energy

This new register structure enables the configuration of multiple pulses with the same energy type, each with distinct pulse constants, providing greater flexibility in system setup.

Refer to the "PIC32CXMTx Metrology Reference Guide (DS50003461)" for a detailed description.

## 1.5. CF Pulses

The metrology firmware can output the following pulses simultaneously, and they are controlled by PULSE0\_CTRL, PULSE1\_CTRL, and PULSE2\_CTRL:

- PULSE0\_CTRL controls the pulse output from PD17
- PULSE1\_CTRL controls the pulse output from PD18
- PULSE2\_CTRL controls the pulse output from PD19

The pulse module supports the following features: ENABLE, DETENT, POLARITY, OVERRIDE, ACC\_HOLD, TYPE, and WIDTH.

All features can be changed at run time except for the POLARITY feature. If POLARITY changed, it will take effect only after the metrology is reset.

Refer to the "PIC32CXMTx Metrology Reference Guide (DS50003461)" for a detailed description.

#### **Example:**

Enable the first pulse and set DETENT = DETENT\_ABSOLUTE, negative polarity, pulse type = TYPE\_P\_T\_F (total active energy), and the pulse width is 40 ms.

Then, it is recommended to set PULSE\_CTRL0 = 0x90014880.

## **1.6. Creep (Start-up/No load)**

The metrology firmware includes support for start-up and no load (creep) detection features. The following creep thresholds are available:

- Global creeps, affecting the pulses and the pulse accumulators ACC\_Tx:
  - CREEP\_THRESHOLD\_I
  - CREEP\_THRESHOLD\_P
  - CREEP\_THRESHOLD\_Q
  - CREEP\_THRESHOLD\_S
- Per-phase creeps, affecting the pulses and the pulse accumulators ACC\_Tx, and additionally the integration period and per-cycle accumulators:
  - CREEP\_THRESHOLD\_I\_A
  - CREEP\_THRESHOLD\_I\_B
  - CREEP\_THRESHOLD\_I\_C
  - CREEP\_THRESHOLD\_P\_A
  - CREEP\_THRESHOLD\_P\_B
  - CREEP\_THRESHOLD\_P\_C
  - CREEP\_THRESHOLD\_Q\_A
  - CREEP\_THRESHOLD\_Q\_B
  - CREEP\_THRESHOLD\_Q\_C

#### **Current creep:**

Energy measurements ( $I^2$ -hour, Watt-hour, Var-hour, VA-hour) for any phase x (x = A, B, or C) will not be accumulated if the RMS current value is below the global threshold, CREEP\_THRESHOLD\_I. The individual thresholds enable the configuration of distinct creep thresholds for each phase, allowing for more precise control and customization.

#### **Active power creep:**

The total active energy is accumulated only when the active energy in a full cycle is greater than CREEP\_THRESHOLD\_P.

Similarly, active energy for each individual phase (A, B, or C) is accumulated only when the phase's active energy in a full cycle exceeds its respective threshold, CREEP\_THRESHOLD\_P\_x.

#### **Reactive power creep:**

The total reactive energy is accumulated only when the reactive energy in a full cycle is greater than CREEP\_THRESHOLD\_Q.

Similarly, reactive energy for each individual phase (A, B, or C) is accumulated only when the phase's reactive energy in a full cycle exceeds its respective threshold, CREEP\_THRESHOLD\_Q\_x.

#### **Apparent power creep:**

The total apparent energy is accumulated only when the apparent energy in a full cycle is greater than CREEP\_THRESHOLD\_S.

The “PIC32CXMTx Metrology Reference Guide (DS50003461)” provides example calculations for each one of the thresholds.

## 1.7. AFE

When using the PIC32CXMTC, the connected AFE (ATSENSE301, MCP3910, MCP3912, MCP3913, or MCP3914) is selected by the AFE\_SELECTION register. When using the PIC32CXMTSH (internal ATSENSE203), this register is not used.

The AFE\_CTRL\_0 register configures the selected AFE, mainly the PGA gains. This register has a different meaning depending on the selected AFE. For PIC32CXMTC + MCP3910 this register is not used.

The CHANNEL\_MATRIX register allows to map each physical channel (0, 1, 2, 3, 4, 5, 6, or 7) to a specific logical channel (I\_A, V\_A, I\_B, V\_B, I\_C, V\_D, I\_N, or V\_D). When using PIC32CXMTSH or PIC32CXMTC + ATSENSE301, channels 0, 1, 3, and 5 (differential channels) should be used for currents and channels 2, 4, and 6 (single-ended channels) should be used for voltages.

Several configuration examples are given below.

### 1.7.1. PIC32CXMTSH, PGA = 1, CH1: I\_A, CH2: V\_A, CH3: I\_B, CH4: V\_B

AFE\_CTRL\_0 = 0x00000000

CHANNEL\_MATRIX = 0xFFFF3210F

### 1.7.2. PIC32CXMTSH, PGA = 2, CH1: I\_B, CH2: V\_A, CH3: I\_A, CH4: Not used

AFE\_CTRL\_0 = 0x00000014

CHANNEL\_MATRIX = 0xFFFF012F

### 1.7.3. PIC32CXMTC + ATSENSE301, PGA = 4, CH0: I\_N, CH1: I\_A, CH2: V\_A, CH3: I\_B, CH4: V\_B, CH5: I\_C, CH6: V\_C

AFE\_SELECTION = 0x00000000

AFE\_CTRL\_0 = 0x000000AA

CHANNEL\_MATRIX = 0xF5432106

### 1.7.4. PIC32CXMTC + ATSENSE301, PGA = 8, CH0: I\_N, CH1: I\_A, CH2: V\_A, CH3: I\_C, CH4: V\_C, CH5: I\_B, CH6: V\_B

AFE\_SELECTION = 0x00000000

AFE\_CTRL\_0 = 0x000000FF

CHANNEL\_MATRIX = 0xF3254106

### 1.7.5. PIC32CXMTC + 3xMCP3910, CH0: I\_A, CH1: V\_A, CH2: I\_B, CH3: V\_B, CH4: V\_B, CH5: I\_C

AFE\_SELECTION = 0x00000001

CHANNEL\_MATRIX = 0xFF543210

### 1.7.6. PIC32CXMTC + 4xMCP3910, CH0: I\_A, CH1: V\_A, CH2: I\_B, CH3: V\_B, CH4: V\_B, CH5: I\_C, CH6: I\_C, CH7: V\_C

AFE\_SELECTION = 0x00000002

CHANNEL\_MATRIX = 0x76543210

### 1.7.7. PIC32CXMTC + MCP3912, PGA = 1, CH0: I\_A, CH1: I\_B, CH2: V\_A, CH3: V\_B

AFE\_SELECTION = 0x00000003

AFE\_CTRL\_0 = 0x0B000000 (dithering: on, maximum strength; boost: x1)

CHANNEL\_MATRIX = 0xFFFF3120

**1.7.8. PIC32CXMTc + MCP3913, PGA = 2, CH0: I\_A, CH1: I\_B, CH2: I\_C, CH3: V\_A, CH4: V\_B, CH5: V\_C**

AFE\_SELECTION = 0x00000004

AFE\_CTRL\_0 = 0x0E000049 (dithering: on, medium strength; boost: x2)

CHANNEL\_MATRIX = 0xFF531420

**1.7.9. PIC32CXMTc + MCP3914, PGA = 4, CH0: I\_A, CH1: I\_B, CH2: I\_C, CH3: I\_N, CH4: V\_A, CH5: V\_B, CH6: V\_C, CH7: V\_D**

AFE\_SELECTION = 0x00000005

AFE\_CTRL\_0 = 0x05002492 (dithering: on, minimum strength; boost: x0.66)

CHANNEL\_MATRIX = 0x75316420

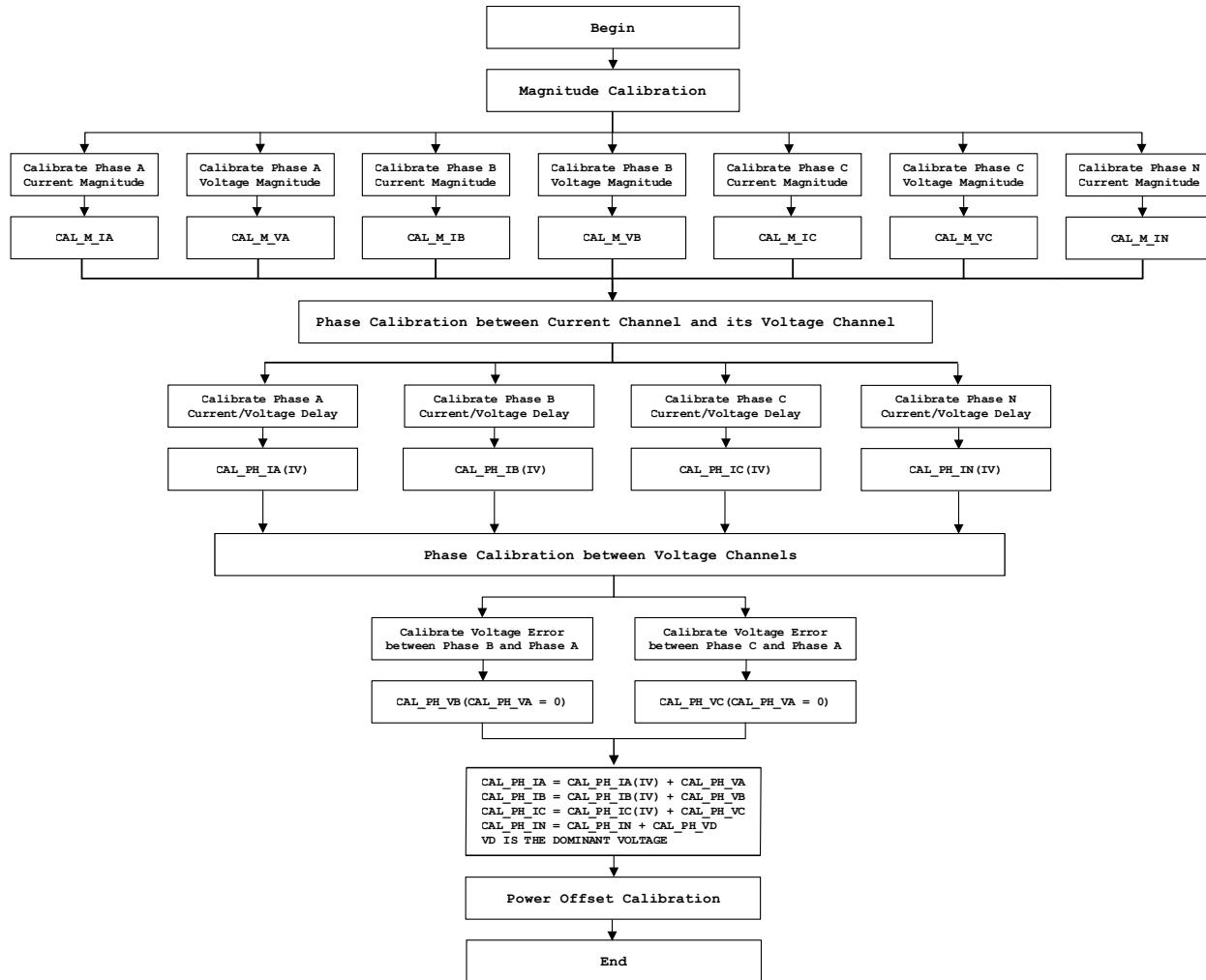
## 1.8. Other Features

Refer to the "PIC32CXMTx Metrology Reference Guide (DS50003461)" for a detailed description of the registers.

## 2. Calibration

It is recommended to calibrate and verify each meter before delivery. The metrology library can be calibrated after it is configured correctly. The following figure illustrates the metrology firmware calibration flowchart:

**Figure 2-1.** Firmware Calibration Flowchart with Neutral Current



Since all DSP filters are mathematically correct, once the magnitude and phase have been properly calibrated, both active power and reactive power will be automatically correct.

### 2.1. Magnitude

CAL\_M\_Ix (x = A, B, C, N) and CAL\_M\_Vx (x = A, B, C, D) are used to calibrate the current and voltage magnitudes of phase x. Calibration may be iterative, using prior or old magnitude calibration factors to perform the next calibration cycle, or they may be set to 0x20000000 (unity) by the application prior to calibration.

The following formulas are used to calibrate the magnitude of phase x:

$$CAL\_M\_Vx\_new = CAL\_M\_Vx\_old \times \frac{Vx\_RMS\_IN}{\frac{K\_Vx}{2^{10}} \times \sqrt{\frac{ACC\_V\_x}{N \times 2^{40}}}}$$

$$CAL\_M\_Ix\_new = CAL\_M\_Ix\_old \times \frac{Ix\_RMS\_IN}{\frac{K\_Ix}{2^{10}} \times \sqrt{\frac{ACC\_Ix}{N \times 2^{40}}}}$$

Where,

- $x = [A, B, C, N]$  for  $CAL\_M\_Ix$  and  $x = [A, B, C, D]$  for  $CAL\_M\_Vx$ , and:
- $Ix\_RMS\_IN$  is the input test current, with units [A]
- $Vx\_RMS\_IN$  is the input test voltage, with units [V]
- $K\_Ix$  is the current conversion factor in uQ22.10
- $K\_Vx$  is the voltage conversion factor in uQ22.10
- $N$  is the number of samples in the integration period
- $ACC\_Ix$  is the accumulated all harmonics current quantity
- $ACC\_Vx$  is the accumulated all harmonics voltage quantity

#### Example:

An integration period of 1 second is used to gather the following accumulator values calibrate phase-A, with conditions: 120V, 50A, with the old calibrations set to unity (1.0000 = 0x20000000 [sQ2.29]).

- $K\_IA = 0x9A522$  [uQ22.10] = 617.283
- $K\_VA = 0x19CC00$  [uQ22.10] = 1651
- $N = 4000$  (number of samples in integration period)
- $ACC\_I\_A = 0x1AF61FD09BBD = 29644398042045$
- $ACC\_V\_A = 0x144B58A21387 = 22313842119559$

$$CAL\_M\_Ix\_new = CAL\_M\_Ix\_old \times \frac{Ix\_RMS\_IN}{\frac{K\_Ix}{2^{10}} \times \sqrt{\frac{ACC\_Ix}{N \times 2^{40}}}} = \\ = 1.0000 \times \frac{50 A}{617.283 \times \sqrt{\frac{29644398042045}{4000 \times 2^{40}}}} = 0.986607 = 0x1F924941 [sQ2.29]$$

$$CAL\_M\_Vx\_new = CAL\_M\_Vx\_old \times \frac{Vx\_RMS\_IN}{\frac{K\_Vx}{2^{10}} \times \sqrt{\frac{ACC\_Vx}{N \times 2^{40}}}} = \\ = 1.0000 \times \frac{120 V}{1651 \times \sqrt{\frac{22313842119559}{4000 \times 2^{40}}}} = 1.020415 = 0x20A73DB4 [sQ2.29]$$

**Note:** The  $CAL\_M\_VD$  register is used for magnitude calibration of the 8<sup>th</sup> channel of the MCP3914 AFE. This channel is not displayed in the calibration graph, as it is typically reserved for application-specific measurements that are not necessarily related to metrology.

## 2.2. Phase Delay

$CAL\_PH\_Ix(x = A, B, C, N)$  and  $CAL\_PH\_Vx(x = A, B, C)$  are used to align the phase delays between each pair of current and voltage channels, and to optionally equalize the phase delays between voltage channels. All phase shift coefficients used by the metrology DSP must be normalized to equivalent linear-phase shift amounts at 60 Hz.

Phase calibration steps are given below:

1. Phase calibration between current channel and its voltage channel.
2. Phase calibration between voltage channels (optional).

If interphase vector manipulation or optimal phase-phase voltage measurement are not required, then step 2 is optional. If there is no need to make phase calibration between voltage channels, set all CAL\_PH\_Vx registers to the value: 0x00000000.

However, if interphase vector manipulation is desired or it is desired to achieve the highest accuracy in phase-phase voltage measurements, then it is required to adjust the voltage phase correction coefficients.

Usually, acceptable calibration performance for energy-types of values may be obtained with a single calibration pass using the data from one integration period (usually 1 second or longer) using voltage and current values read directly from a standard or measurement device, with all phase correction coefficients computed simultaneously with the magnitude correction factors from that same set of integration data.

To achieve the highest accuracy in voltage and/or current measurements, it is a common practice to first calibrate the voltage or current channels individually, typically using a pulse reference standard. For example, if all current channels are pulse magnitude calibrated for A<sup>2</sup>hr, then all the remaining calibration coefficients (voltage magnitude, current phase and voltage phase correction factors) may be determined with a single additional calibration pass using one set of integration data.

## 2.2.1. Phase Calibration Between Current and Voltage Channels

Phase calibration may be accomplished using whatever current-voltage phase angle the user desires,  $\theta_{VI}$ . Calibration may be iterative, using prior or old phase calibration factors to perform the next calibration cycle, or they may be set to 0x00000000 (zero) by the application prior to calibration.

### 2.2.1.1. Calculating Phase Calibration Factor Using Accumulator Values

The following formula is used to calibrate the phase delay of phase x making use of values from the integration period accumulators:

$$CAL\_PH\_Ix_{IV} = \frac{\left( \arctan \left( \frac{ACC\_Q\_x\_F}{ACC\_P\_x\_F} \right) - \theta_{VI} \right)}{180^\circ} \times \frac{60Hz}{f\_line} \times 2^{31}$$

$CAL\_PH\_Vx = 0x00000000$

$CAL\_PH\_Ix = CAL\_PH\_Ix_{IV}$  (if voltage channel phase calibration is not required)

Where:

- ACC\_Q\_x\_F – Reactive power fundamental-only integration accumulator value.
- ACC\_P\_x\_F – Active power fundamental-only integration accumulator value.
- $\theta_{VI}$  – Test condition phase angle between voltage and current (+ inductive).
- f\_line – The power line frequency used for calibration.

**Note:** The above calibration equation can be used for manual calibration at any angle, while the auto calibration routines provided in the demonstration application program may be constrained to run at PF = 0.5Lag (60° lagging) condition only.

**Note:** For calibrating the neutral current phase delay, the fictitious accumulators ACC\_Q\_x\_F and ACC\_P\_x\_F have been added. These are computed using the neutral current and the dominant voltage.

#### Example:

An integration period of 1 second is used to gather the following accumulator values used for calibration, with conditions: 120V, 30A, PF = 0.5 Lag (50 Hz), K\_V = 11557, K\_I = 308.642

ACC\_P\_X\_F = 0x33C7784C5B = 222389881947

ACC\_Q\_X\_F = 0x5A1E99C15E = 387060449630

$$\begin{aligned} CAL\_PH\_Ix_{IV} &= \frac{\left(\arctan\left(\frac{Q_x}{P_x}\right) - \theta_{VI}\right)}{180^\circ} \times \frac{60Hz}{f\_line} \times 2^{31} \\ &= \frac{\left(\arctan\left(\frac{387060449630}{222389881947}\right) - 60^\circ\right)}{180^\circ} \times \frac{60Hz}{50Hz} \times 2^{31} = 0x001A36E3 \end{aligned}$$

**Note:** In the above discussion and example, phase calibration factors are computed for the current channels, regardless of whether voltage-voltage phase correction is computed. When phase calibration between voltage channels is not desired, all other calibration factors (magnitude and current channel phase correction factors) may be computed from accumulator registers from a single integration period. For best results when phase calibration between voltage channels is desired, first calibrate and apply all magnitude gain factors before measuring and calibrating the voltage phase correction values. For additional information, refer to the [Phase Calibration Between Voltage Channels](#).

### 2.2.1.2. Calculating Phase Calibration Factor Using Pulse Calibration Error

Another method to calibrate the phase delay is using the CF pulse error.

Before calibrating the phase delay, set PF to 0.5 Lag (inductive), CAL\_PH\_Ix (x = A, B, C, N) and CAL\_PH\_Vx (x = A, B, C) to 0x00000000.

The following formulas are used to calculate the phase calibration constant of phase x:

$$\begin{aligned} CAL\_PH\_Ix &= -\frac{\text{percent error}}{100 \times \sqrt{3} \times \pi} \times \frac{60Hz}{f\_line} \times 2^{31} \\ CAL\_PH\_Vx &= 0 \end{aligned}$$

#### Example:

After magnitude calibration, pulse measurement of a single channel at PF = 0.5 Lag (50 Hz) shows initial channel accuracy of 99.638%, equivalent to a -0.362% error.

$$\begin{aligned} CAL\_PH\_Ix &= -\frac{\text{percent error}}{100 \times \sqrt{3} \times \pi} \times \frac{60Hz}{f\_line} \times 2^{31} = \\ &= -\frac{-0.362\%}{100 \times \sqrt{3} \times \pi} \times \frac{60Hz}{50Hz} \times 2^{31} = (6.6527 \times 10^{-4}) \times \frac{6}{5} \times 2^{31} = 0x001A28D4 \end{aligned}$$

The intermediate quantity (6.6527e-4) provided above, corresponds to a phase shift of +0.12° at 50 Hz, but needs to be normalized to an equivalent linear-phase shift at 60 Hz of +0.144°. All phase shift coefficients used by the metrology DSP must be normalized to equivalent linear-phase shift values at 60 Hz.

**Note:** When using the pulse method, each phase must be calibrated independently.

### 2.2.1.3. Calculating Phase Calibration Factor in the Presence of Large Parasitic Reactive Load

Some applications may require calibration in the presence of a noticeable parasitic reactive load. In those applications, optimal calibration will be obtained if that parasitic load can be temporarily removed. However, if the parasitic load cannot be removed during calibration, then the arctan() approach of [Calculating Phase Calibration Factor Using Accumulator Values](#) is not recommended, but rather, it is suggested to set test conditions with a considerable reactive test load, such as using a  $\theta_{VI} = 60^\circ$ , PF = 0.5, and use the arccos() approach:

$$CAL\_PH\_Ix_{IV} = \frac{\left(\arccos\left(\frac{P_{\text{measured}}}{V_{\text{RMS}} \times I_{\text{RMS}}}\right) - \theta_{VI}\right)}{180^\circ} \times \frac{60Hz}{f\_line} \times 2^{31}$$

## 2.2.2. Phase Calibration Between Voltage Channels

When phase-to-phase vector measurement or manipulation is necessary, it is recommended to correct the phase errors among all voltage channels. One voltage phase, usually Phase-A, is chosen as a reference that all other voltages will be corrected to. The *Law of Cosines* is used to determine voltage phase correction factors using the fundamental only integration accumulator values.

*CAL\_PH\_VA = 0x00000000 (reference phase)*

The following formulas are used to calibrate the phase errors between the remaining voltage phases:

To phase-calibrate VB (relative to VA):

$$\begin{aligned} \text{CAL\_PH\_VB} &= \frac{\left( \arccos\left(\frac{V_{AB}^2 - V_A^2 - V_B^2}{-2 \times V_A \times V_B}\right) - \theta_{VV}^o \right)}{180^\circ} \times \frac{60\text{Hz}}{f_{line}} \times 2^{31} \\ &= \frac{\left( \arccos\left(\frac{V_{AB\_F} - V_{A\_F} - V_{B\_F}}{-2\sqrt{V_{A\_F} \times V_{B\_F}}}\right) - \theta_{VV}^o \right)}{180^\circ} \times \frac{60\text{Hz}}{f_{line}} \times 2^{31} \end{aligned}$$

Where:

$V_A$  = RMS voltage of Phase-A

$V_B$  = RMS voltage of Phase-B

$V_{AB}$  = Inter-phase RMS voltage between Phase-A and Phase-B

$V_{A\_F}$  = Integration period accumulator value for Phase-A voltage (fundamental)

$V_{B\_F}$  = Integration period accumulator value for Phase-B voltage (fundamental)

$V_{AB\_F}$  = Integration period accumulator value for Phase-A to Phase-B voltage (fundamental)

$\theta_{VV}$  = Phase angle between the two voltage phases [in degrees]

Likewise, to phase-calibrate VC (relative to VA):

$$\begin{aligned} \text{CAL\_PH\_VC} &= \frac{\left( \theta_{VV}^o - \arccos\left(\frac{V_{CA}^2 - V_C^2 - V_A^2}{-2 \times V_C \times V_A}\right) \right)}{180^\circ} \times \frac{60\text{Hz}}{f_{line}} \times 2^{31} \\ &= \frac{\left( \theta_{VV}^o - \arccos\left(\frac{V_{CA\_F} - V_{C\_F} - V_{A\_F}}{-2\sqrt{V_{C\_F} \times V_{A\_F}}}\right) \right)}{180^\circ} \times \frac{60\text{Hz}}{f_{line}} \times 2^{31} \end{aligned}$$

Then, the total phase corrections for the current channels become:

$CAL\_PH\_IA = CAL\_PH\_IA_{IV} + CAL\_PH\_VA$

$CAL\_PH\_IB = CAL\_PH\_IB_{IV} + CAL\_PH\_VB$

$CAL\_PH\_IC = CAL\_PH\_IC_{IV} + CAL\_PH\_VC$

### Example:

An integration period of 1 second is used to gather the following accumulator values used for calibration, with conditions: 120V, 30A, PF = 0.5 Lag (measured at 50 Hz),  $K_V = 11557$ ,  $K_I = 308.642$

- ACC\_V\_A\_F = 0x144BD23C9BDE = 22315882290142
- ACC\_V\_B\_F = 0x1454C5C79B64 = 22354328001380
- ACC\_V\_C\_F = 0x144FAD879049 = 22332446314569
- ACC\_V\_AB\_F = 0x 3CE0EC510A7B = 66936735074939

- Acc\_V\_CA\_F = 0x 3CFB87060C83 = 67050999778435

$$\begin{aligned}
 CAL\_PH\_VB &= \frac{\left( \arccos\left(\frac{V_{AB}^2 - V_A^2 - V_B^2}{-2 \times V_A \times V_B}\right) - \theta_{VV}^o \right)}{180^\circ} \times \frac{60Hz}{f\_line} \times 2^{31} \\
 &= \frac{\left( \arccos\left(\frac{V\_AB\_F - V\_A\_F - V\_B\_F}{-2\sqrt{V\_A\_F \times V\_B\_F}}\right) - \theta_{VV}^o \right)}{180^\circ} \times \frac{60Hz}{f\_line} \times 2^{31} \\
 &= \frac{\left( \arccos\left(\frac{66936735074939 - 22315882290142 - 22354328001380}{-2\sqrt{22315882290142 \times 22354328001380}}\right) - 120^\circ \right)}{180^\circ} \times \frac{60Hz}{50Hz} \times 2^{31} \\
 &= \frac{(\arccos(-0.4984649) - 120^\circ)}{180^\circ} \times \frac{60Hz}{50Hz} \times 2^{31} = \frac{(119.89849^\circ - 120^\circ) \times \frac{6}{5} \times 2^{31}}{180^\circ} = 0xFFE9D32D
 \end{aligned}$$

$$\begin{aligned}
 CAL\_PH\_VC &= \frac{\left( \theta_{VV}^o - \arccos\left(\frac{V_{CA}^2 - V_C^2 - V_A^2}{-2 \times V_C \times V_A}\right) \right)}{180^\circ} \times \frac{60Hz}{f\_line} \times 2^{31} \\
 &= \frac{\left( \theta_{VV}^o - \arccos\left(\frac{V\_CA\_F - V\_C\_F - V\_A\_F}{-2\sqrt{V\_C\_F \times V\_A\_F}}\right) \right)}{180^\circ} \times \frac{60Hz}{f\_line} \times 2^{31} \\
 &= \frac{\left( 120^\circ - \arccos\left(\frac{67050999778435 - 22332446314569 - 22315882290142}{-2\sqrt{22332446314569 \times 22315882290142}}\right) \right)}{180^\circ} \times \frac{60Hz}{50Hz} \times 2^{31} \\
 &= \frac{(120^\circ - \arccos(-0.5017584))}{180^\circ} \times \frac{60Hz}{50Hz} \times 2^{31} = \frac{(120^\circ - 120.11640136^\circ) \times \frac{6}{5} \times 2^{31}}{180^\circ} = 0xFFE6925D
 \end{aligned}$$

**Note:** For the best results when phase calibration between voltage channels is desired, first calibrate and apply all magnitude gain factors before measuring and calibrating the voltage phase correction values.

## 2.3. Power Offset

The metrology firmware supports two methods of power offset calibration to solve the power offset issue caused by the voltage cross-talk or chip itself:

- Single value per-cycle offset corrections for P, Q, and S
- Per-phase per-sample offset correction values for P and Q

### 2.3.1. Single-Value Per-Cycle Power Offset Approach

The three single-value power offset compensation values only affect pulsed outputs (not integration register values) and are named as follows:

- POWER\_OFFSET\_P is total active energy (Wh) in a full cycle.
- POWER\_OFFSET\_Q is total reactive energy (Varh) in a full cycle.
- POWER\_OFFSET\_S is total apparent energy (VAh) in a full cycle.

POWER\_OFFSET\_P, POWER\_OFFSET\_Q, and POWER\_OFFSET\_S are stored in the sQ1.30 format.

The power offset depends on the DETENT type in PULSE\_CTRLx:

- Energy = Input Energy – Power Offset, when DETENT is NET, DELIVERED, or GENERATED
- Energy = |Input Energy| – Power Offset, when DETENT is ABSOLUTE

### 2.3.2. Per-Phase Per-Sample Power Offset Approach

The per-phase power offset compensation values affect both pulsed outputs and integration register values and are named as follows:

- POWER\_OFFSET\_P\_A, POWER\_OFFSET\_P\_B, POWER\_OFFSET\_P\_C
- POWER\_OFFSET\_Q\_A, POWER\_OFFSET\_Q\_B, POWER\_OFFSET\_Q\_C

POWER\_OFFSET\_P\_x is the per-phase active energy offset value in units of [W-samples scaled] with the same scaling as the 64-bit active energy accumulator P\_x.

POWER\_OFFSET\_Q\_x is the per-phase reactive quadergy offset value in units of [VAR-samples scaled] with the same scaling as the 64-bit reactive quadergy accumulator Q\_x.

Computation of the per-phase POWER\_OFFSET\_P\_x values can be as simple as applying all active voltage phases and zeroing current phases. After integrating over an acceptable period of time (at least 1 second), each 64-bit P\_x accumulator is then divided by the number of samples in the integration period and applied to the POWER\_OFFSET\_P\_x register. If voltage magnitude effects are desired, the application processor may scale POWER\_OFFSET\_P\_x as desired and updated.

A similar approach is used for computation of the POWER\_OFFSET\_Q\_x values.

### 2.3.3. Static vs. Dynamic Power Offsets

If offsets are used for fixed-voltage meter applications, the offsets may be static (computed once and not changed). However, for wide-voltage range meter applications, it is recommended that all power offset values be dynamically changed proportional to the square of the phase voltage ( $V^2$ ).

## 2.4. Application Sequence of Power Offsets and Creeps

This section describes the application sequence for CREEP\_I, CREEP\_I\_x, CREEP\_P, CREEP\_P\_x, CREEP\_Q, CREEP\_Q\_x, CREEP\_S, POWER\_OFFSET\_P, POWER\_OFFSET\_Q, POWER\_OFFSET\_S, POWER\_OFFSET\_Px, and POWER\_OFFSET\_Qx.

The first corrections to be applied are the individual power offsets (POWER\_OFFSET\_Px and POWER\_OFFSET\_Qx), which are applied at a 4 kHz rate for each sample.

The remaining corrections are applied each line cycle:

- The corrections affecting the accumulators (CREEP\_OFFSET\_I\_x, CREEP\_OFFSET\_P\_x and CREEP\_OFFSET\_Q\_x) are applied first
- POWER\_OFFSET\_S (a correction over the RMS current) is applied
- CREEP\_I, which affects all pulse sources, is applied
- POWER\_OFFSET\_P and POWER\_OFFSET\_Q are applied
- CREEP\_P and CREEP\_Q are applied

## 2.5. Conclusions

- After active power is calibrated, reactive power will use the same calibration parameters.
- Three phase voltage and current magnitude can be calibrated at the same time.
- Three phase delays can be calibrated simultaneously by power method.
- Three phase delays can be calibrated independently by error method.
- After the magnitude is calibrated, it will take effect immediately.
- After the phase delay is calibrated, it will take effect at the next integration period.

### 3. Metrology Firmware Special Function

The metrology firmware provides some special functions which make it more powerful.

#### 3.1. Waveform Capture

Before enabling waveform capture, the registers must be set correctly:

##### **CAPTURE\_SOURCE:**

- 0 = Capture 16 kHz data for ADC [sQ1.30]
- 1 = Capture 4 kHz FBW data [sQ2.29] (Full BandWidth = fundamental + harmonics)
- 2 = Capture 4 kHz NBW data [sQ2.29] (Narrow BandWidth = fundamental only)
- 3 = Capture 8 kHz FBW data [sQ2.29] (Full BandWidth = fundamental + harmonics)

##### **CAPTURE\_TYPE:**

- 0 = One-shot Capture mode
- 1 = Continuous Capture modes

One-shot Capture mode is recommended for general purposes; otherwise, the captured data in capture buffer may be not continuous.

##### **CH\_SEL\_Ix/Vx (x = A, B, C, N for Ix, x = A, B, C, D for Vx): Capture Channel Select**

Up to 8 channels of data may be captured at the same time. These registers are used to appoint which channels will be captured.

##### **CAPTURE\_ADDR:**

This register is used to specify the starting address of the waveform capture buffer and is interpreted as a pointer to the 32-bit unsigned integer. The waveform capture buffer must be allocated in core 0 memory spaces.

##### **CAPTURE\_BUFF\_SIZE:**

This register specifies the buffer size in units of DWORD for capture function. It must be divisible by the number of channels selected. The buffer size must not be larger than the allocated size, otherwise, the application code may be corrupted by a buffer overrun.

After all these registers are set correctly, the user can enable the waveform capture function by setting CAPTURE\_EN to 1. Check CAPTURE\_STATUS to get capture status.

The following table provides the capture buffer distribution samples:

Channel IA is selected	All channels are selected	Channel IA and IB are selected
CH_IA_0	CH_IA_0	CH_IA_0
CH_IA_1	CH_VA_0	CH_IB_0
CH_IA_2	CH_IB_0	CH_IA_1
CH_IA_3	CH_VB_0	CH_IB_1
CH_IA_4	CH_IC_0	CH_IA_2
CH_IA_5	CH_VC_0	CH_IB_2
CH_IA_6	CH_IN_0	CH_IA_3
CH_IA_7	CH_VD_0	CH_IB_3
CH_IA_8	CH_IA_1	CH_IA_4
—	CH_VA_1	CH_IB_4
—	CH_IB_1	—
—	CH_VB_1	—

#### Waveform Capture (continued)

Channel IA is selected	All channels are selected	Channel IA and IB are selected
—	CH_IC_1	—
—	CH_VC_1	—
—	CH_IN_1	—
—	CH_VD_1	—
—	CH_IA_2	—
—	CH_VA_2	—
—	CH_IB_2	—

**Note:** All captured data is after Vref compensation was applied and are scaled values (normalized by the appropriate K\_Ix and K\_Vx). In the case of 16 kHz captured data, the calibration constants were not applied.

## 3.2. Harmonic Analysis

Harmonic analysis control-related registers are allocated in the HARMONIC\_CTRL and FEATURE\_CTRL.

The HARMONIC\_CTRL.HARMONIC\_EN (bit 31) enables or disables harmonic computation. The 0 to 30 bits are used to select the specific harmonics to be computed. Accurate results from the analysis are obtained after a complete integration period has elapsed. Therefore, the application must disregard the results generated during the integration period in which the analysis was enabled or the harmonic selection was modified.

The FEATURE\_CTRL register allows the selection of channels enabled for harmonic computation. By default, all channels are enabled.



Although the control register can enable up to 31 harmonic orders, the frequency response may be limited by the metrology filters or the input network anti-aliasing filters. With respect to the metrology filters, the accuracy is better than 0.007% up to 1386 Hz, ensuring an extremely accurate response up to the 21st harmonic order (considering a fundamental frequency of 60 Hz, with a 10% deviation). However, the response remains relatively flat up to 1650 Hz, with an error margin of up to 0.05%.

**Note:** When enabled, the harmonic analysis result is updated every integration period. The INTEGRATION\_IRQ will be generated at the end of the integration period, and this interrupt can be used to update the harmonic analysis result.

## 4. Monitor Metrology Firmware

It is essential to monitor the operation of the metrology firmware to ensure it is functioning correctly with the application code.

When the metrology is running, these control registers may be changed dynamically, but may induce measurement perturbations if large changes are made: CREEP\_X\_EN, PULSE\_X\_CTRL, PULSE\_X\_K\_t, POWER\_OFFSET\_CTRL, POWER\_OFFSET\_P, POWER\_OFFSET\_Q, POWER\_OFFSET\_P\_x, POWER\_OFFSET\_Q\_x, K\_Ix, K\_Vx, CAL\_M\_Ix, CAL\_M\_Vx, CAL\_PH\_Ix, CAL\_PH\_Vx, and CAPTURE control registers.

The following registers will be cleared by metrology firmware automatically when the task is finished: V\_MAX\_RESET, I\_MAX\_RESET, and CAPTURE\_EN (one-shot mode).

In the default configuration for the provided metrology examples, the following three interrupts will be generated:

- HALF\_CYCLE\_IRQ – Generated every half line cycle
- CYCLE\_IRQ – Generated every full line cycle
- INTEGRATION\_IRQ – Generated every integration period

When these interrupts are generated, related status registers and accumulated quantities are already updated and may be copied using the application processor.

It is recommended that the application monitors the metrology library running state. If the metrology firmware flags are abnormal, the application code must reset the metrology firmware and restore control register settings.

## 5. Revision History

### Revision C - 11/2025

The following updates were performed in this revision:

Document	<ul style="list-style-type: none"> <li>Minor changes of format</li> <li>Compatible with Metrology Library version v03.04.00</li> </ul>
Configuration	<ul style="list-style-type: none"> <li>Add Interrupt threshold in <a href="#">Sag, Swell, and Interrupt</a> section</li> <li>Updated <a href="#">Pulse Test Constant</a> section</li> <li>Updated <a href="#">Creep (Start-up/No load)</a> section</li> <li>Changed EMAFE section by <a href="#">AFE</a> section and added subsections</li> <li>Removed reference in <a href="#">Other Features</a> section</li> </ul>
Calibration	<ul style="list-style-type: none"> <li>Added <math>D</math> in CAL_M_Vx and note in <a href="#">Magnitude</a> section</li> <li>Added <math>CREEP\_I_x</math>, <math>CREEP\_P_x</math>, <math>CREEP\_Q_x</math> and first bullet in <a href="#">Application Sequence of Power Offsets and Creeps</a> section</li> </ul>
Metrology Firmware Special Function	<ul style="list-style-type: none"> <li>Added <math>D</math> in CH_SEL_Vx in <a href="#">Waveform Capture</a> section</li> <li>Added <math>CH\_VD\_0</math> and <math>CH\_VD\_1</math> in the table of <a href="#">Waveform Capture</a> section</li> </ul>
Monitor Metrology Firmware	<ul style="list-style-type: none"> <li>Changed <math>P\_K_t</math>, <math>Q\_K_t</math>, and <math>I\_K_t</math> by <math>PULSE_K_t</math> in <a href="#">Monitor Metrology Firmware</a></li> </ul>

### Revision B - 04/2025

The following updates were performed in this revision:

Document	<ul style="list-style-type: none"> <li>Minor changes of format</li> <li>Compatible with Metrology Library version 3.03.00</li> <li>Changed <i>Microchip Metrology data sheet</i> by <i>PIC32CXMTx Metrology Reference Guide (DS50003461)</i></li> </ul>
Configuration	<ul style="list-style-type: none"> <li>Added <math>S\_K_t</math> in <a href="#">Pulse Test Constant</a> section</li> <li>Added <math>CREEP\_THRESHOLD\_S</math> in <a href="#">Creep (Start-up/No load)</a> section</li> </ul>
Calibration	<ul style="list-style-type: none"> <li>Updated <a href="#">Figure 2-1</a></li> <li>Added note in <a href="#">Calculating Phase Calibration Factor Using Accumulator Values</a> section</li> <li>Updated <a href="#">Power Offset</a> section</li> <li>Added <math>POWER\_OFFSET\_S</math> in <a href="#">Single-Value Per-Cycle Power Offset Approach</a> section</li> <li>Added <a href="#">Application Sequence of Power Offsets and Creeps</a> section</li> </ul>
Metrology Firmware Special Function	<ul style="list-style-type: none"> <li>Updated <a href="#">Harmonic Analysis</a> section</li> </ul>

### Revision A - 12/2022

Document	<ul style="list-style-type: none"> <li>Initial release</li> <li>Metrology library version v3.0.0b</li> </ul>
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